

Data Sheet

January 2002

8.4A, 100V, 0.270 Ohm, N-Channel Power MOSFETs

These are N-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

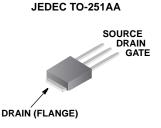
Formerly developmental type TA09594.

Ordering Information

PART NUMBER	PACKAGE	BRAND
IRFR120	TO-252AA	IFR120
IRFU120	TO-251AA	IFU120

NOTE: When ordering, use the entire part number. Add the suffix T to obtain the TO-252AA variant in the tape and reel, i.e., IRFR120T.

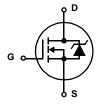
Packaging



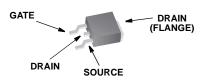
Features

- 8.4A, 100V
- r_{DS(ON)} = 0.270Ω
- Single Pulse Avalanche Energy Rated
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



JEDEC TO-252AA



Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	IRFR120, IRFU120	UNITS
Drain to Source Voltage (Note 1)V _{DS}	100	V
Drain to Gate Voltage (R _{GS} = 20kΩ) (Note 1)V _{DGR}	100	V
Continuous Drain Current	8.4	A
$T_{C} = 100^{\circ}C$ I_{D}	5.9	A
Pulsed Drain Current (Note 3)	34	А
Gate to Source Voltage	±20	V
Maximum Power Dissipation	50	W
Linear Derating Factor	0.33	W/ ^o C
Single Pulse Avalanche Energy Rating (Figure 14) E _{AS}	36	mJ
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering		°c
Leads at 0.063in (1.6mm) from Case for 10s	300	C
Package Body for 10s, See Techbrief 334	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $150^{\circ}C$.

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	I _D = 250μA, V _{GS} = 0V (Figure 10)		100	-	-	V
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 250 \mu A$		2.0	-	4.0	V
Zero Gate Voltage Drain Current	IDSS	V_{DS} = Rated BV _{DSS} , V_{GS} = 0V		-	-	25	μA
		$V_{DS} = 0.8 \text{ x Rated BV}_{DSS}, V_{GS} = 0V, T_J = 150^{\circ}C$		-	-	250	μA
On-State Drain Current (Note 2)	I _{D(ON)}	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}$		8.4	-	-	А
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V$		-	-	±500	nA
Drain to Source On Resistance (Note 2)	r _{DS(ON)}	I _D = 5.9A, V _{GS} = 10V (Figu	res 8, 9)	-	0.25	0.27	Ω
Forward Transconductance (Note 2)	9fs	$V_{DS} \ge 50V$, $I_D = 5.9A$ (Figur	re 12)	2.8	4.2	-	S
Turn-On Delay Time	t _{d(ON)}	$V_{DD} = 50V, I_D \cong 8.4A, R_{GS}$	= 18Ω, R _L = 5.1Ω	-	8.8	13	ns
Rise Time	t _r	MOSFET Switching Times a	,	-	30	45	ns
Turn-Off Delay Time	t _{d(OFF)}	 Independent of Operating Temperature 		-	19	29	ns
Fall Time	t _f			-	20	30	ns
Total Gate Charge (Gate to Source + Gate to Drain)	Q _{g(TOT)}	V_{GS} = 10V, I_D = 8.4A, V_{DS} = 0.8 x Rated BV _{DSS} , $I_{G(REF)}$ = 1.5mA (Figure 14) Gate Charge is Essentially Independent of Operating Temperature		-	9.7	15	nC
Gate to Source Charge	Q _{gs}			-	2.2	3.3	nC
Gate to Drain "Miller" Charge	Q _{gd}			-	2.3	3.4	nC
Input Capacitance	C _{ISS}	$V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$ (Figure 11)		-	350	-	pF
Output Capacitance	C _{OSS}			-	130	-	pF
Reverse Transfer Capacitance	C _{RSS}			-	24	-	pF
Internal Drain Inductance	LD	Measured from the Drain Lead, 6.0mm (0.25in) from Package to Center of Die	Modified MOSFET Symbol Showing the Internal Device	-	4.5	-	nH
Internal Source Inductance	LS	Measured from the Source Lead, 6.0mm (0.25in) from Package to Source Bonding Pad	Inductances	-	7.5	-	nH
Thermal Resistance, Junction to Case	R _{θJC}		1	-	-	3.0	°C/W
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	Typical Solder Mount		-	-	110	°C/W

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	МАХ	UNITS
Continuous Source to Drain Current	I _{SD}	Modified MOSFET	-	-	8.4	А
Pulse Source to Drain Current (Note 3)	ISDM	Symbol Showing the Integral Reverse P-N Junction Rectifier	-	-	34	A
Source to Drain Diode Voltage (Note 2)	V _{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 8.4A$, $V_{GS} = 0V$ (Figure 13)	-	-	2.5	V
Reverse Recovery Time	t _{rr}	$T_J = 25^{o}C$, $I_{SD} = 8.4A$, $dI_{SD}/dt = 100A/\mu s$	55	110	240	ns
Reverse Recovery Charge	Q _{RR}	$T_J = 25^{0}C$, $I_{SD} = 8.4A$, $dI_{SD}/dt = 100A/\mu s$	0.25	0.53	1.1	μC

NOTES:

- 2. Pulse test: pulse width $\leq 300 \mu s, \, duty \, cycle \leq 2\%.$
- 3. Repetitive rating: pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
- 4. V_{DD} = 25V, starting T_J = 25^oC, L = 770µH, R_G = 25 Ω , Peak I_{AS} = 8.4A.



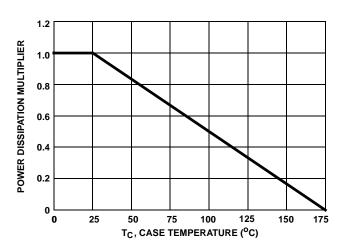


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

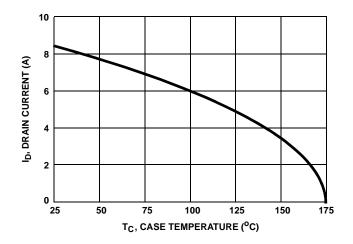
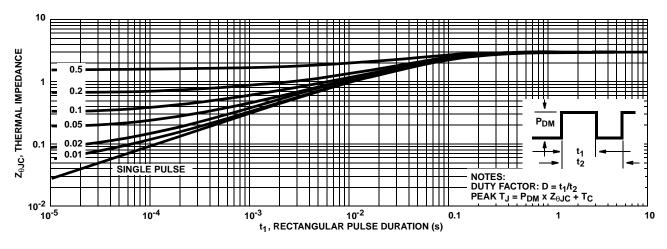
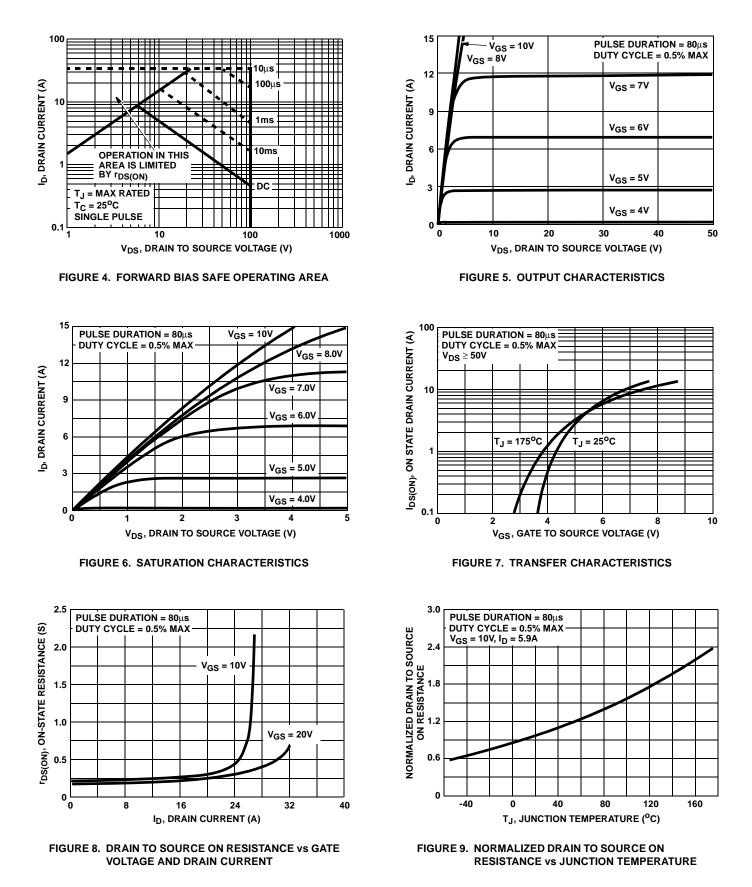


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

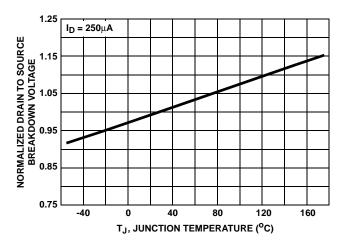




Typical Performance Curves Unless Otherwise Specified (Continued)



Typical Performance Curves Unless Otherwise Specified (Continued)





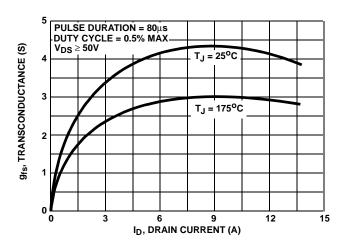


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

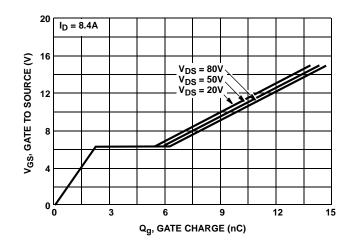


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

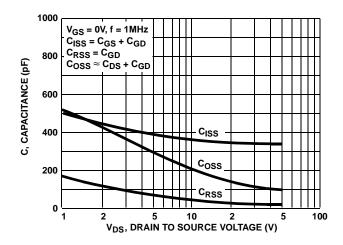


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

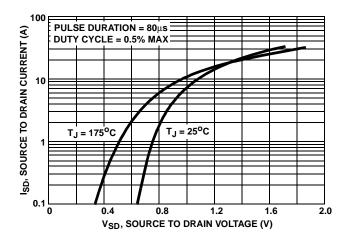


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

Test Circuits and Wa v e f o r m s

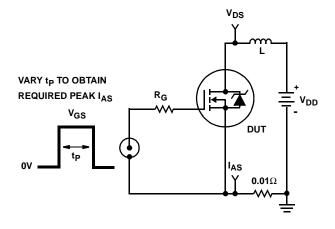


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

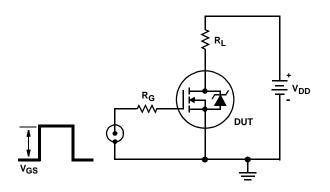


FIGURE 17. SWITCHING TIME TEST CIRCUIT

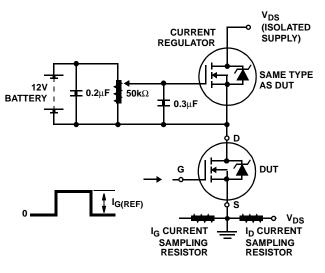


FIGURE 19. GATE CHARGE TEST CIRCUIT

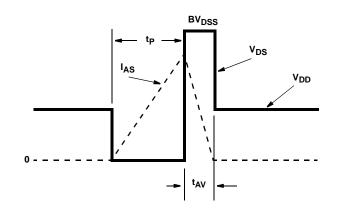


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

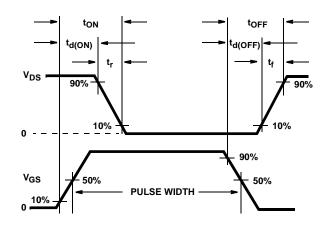


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

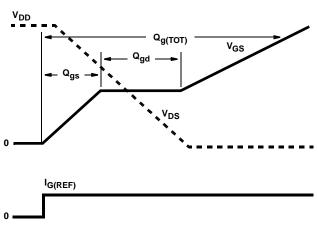


FIGURE 20. GATE CHARGE WAVEFORMS

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